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FORM PTO-1449	ATTY. DKT NO.	01-617	SER. NO.	101824497
	APPLICANT	Endou, et al.		
	FILING DATE	April 15, 2004	GROUP	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS


FOREIGN PATENT DOCUMENTS

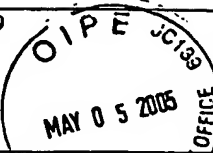
TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
									Eng. Abstract	
JP		JP-A-10-125620 (discussed on page 2 of the specification)	05/15/98	JAPAN						X
JP		JP-A-2000-12846 (discussed on page 2 of the specification)	01/14/00	JAPAN						X

* Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
	8/6/05

FORM PTO-1449		ATTY. DKT NO. 01-617	SER. NO. 10/824,497
		APPLICANT ENDOU et al.	
		FILING DATE April 15, 2004	GROUP 2812

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

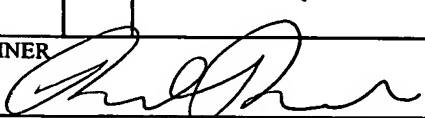
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

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		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO	
									Eng. Abstract	
JP		WO 01/84609	11/8/01	PCT						

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